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Corrigendum

[Regarding Tender for supply of “Automated and Programmable Probe Station for Silicon Multi-Strip Detector Characterization Setup” issued on 04.05.2016]

Ref.No.: DU/PHYSICS/APS

Date: 11-05-2016

With reference to the tenders invited for Supply of “Automated and Programmable Probe Station for Silicon Multi-Strip Detector Characterization Setup”, issued vide this office of undersigned on 04.05.2016, the following changes in the Tender Notice are hereby notified through this Corrigendum for all concerned stakeholders.

1. In Appendix A, in Section 1.2 under sub-sections 1.2.3.1, 1.2.4.1, the line “the capacitance measurements of the order of \sim pF to \sim 10 μ F (or better)” should now be read as
“the capacitance measurements of the order of \sim 0.1 pF to \sim 10 μ F (or better)”
2. In Appendix A, in Section 2.1 under sub-sections 2.1.3, 2.1.4, the line “capacitance measurements of the order of \sim pF to \sim 10 μ F (or better)” should now be read as
“capacitance measurements of the order of \sim 0.1pF to \sim 10 μ F (or better)”
3. In Appendix A, in Section 2.1 under sub-sections 2.1.9, the line “capacitance from pF to μ F” should now be read as
“capacitance from \sim 0.1 pF to μ F”
4. In Appendix A, in Section 2.2 under sub-sections 2.2.2, the line “Microscope movement of 100 mm X 100 mm in X-Y plane with at least 50 mm of pneumatic Z lift with interfacing capability” should now be read as
“Microscope movement of 100 mm X 100 mm in X-Y plane with at least 50 mm of Z lift”

Yours faithfully,

Director